



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

8/Supp
ZDS
7/30/03
Abeyes

Applicant: Jorg-Thomas Zettler

Serial No.: 09/998,446

Filed: Nov. 30, 2001

For: METHOD FOR MEASURING
CHARACTERISTICS, ESPECIALLY
THE TEMPERATURE OF A
MULTI-LAYER MATERIAL WHILE
THE LAYERS ARE BEING BUILT UP

Art Unit: 2877

Examiner: Lyons, Michael A.

CERTIFICATE OF MAILING BY "EXPRESS MAIL"

Express Mail Label No. EV 158861718US

Date of Deposit: July 16, 2003

I hereby certify that this paper or fee is being deposited with the United States Postal Service "Express Mail" Service to Addressee under 37 CFR 1.10 on the date indicated above and is addressed to the Commissioner for Patents, Alexandria, VA 22313-1450

Print Name: ERIKA McDougald

Signature: Erika McDougald

Commissioner for Patents
Alexandria, VA 22313-1450

SUPPLEMENTAL
INFORMATION DISCLOSURE STATEMENT

Sir:

The attention of the Examiner is directed to the enclosed document submitted under 1.97(c)(2) as identified below.

1. K.P. KILLEEN and W.G. BREILAND, "In Situ Spectral Reflectance Monitoring of III-V Epitaxy," Journal of Electronic Materials, Vol. 23, No. 2, 1994, pages 179-183.

The foregoing document is listed on the annexed form PTO Form SB/08B and a copy is enclosed herewith.

The Examiner is invited to consider this material in the examination of the present application and to conduct an independent search.

A fee as set forth in § 1.17(p) is enclosed. The Commissioner is hereby authorized to charge any fees additional fee which may be due, and to credit any overpayment, to Deposit Account No. 14-1263. A duplicate copy of this paper is enclosed.

Please stamp and return the enclosed postcard to acknowledge receipt of the foregoing.

Respectfully submitted,



Mark A. Montana

Registration No. 44,948

July 16, 2003

Norris, McLaughlin & Marcus, PA
220 East 42nd Street – 30th Floor
New York, New York 10017

908-722-0700

101215-75 US